Przemyslaw Gromala

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/3740692/publications.pdf

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12 49 3 3 g-index

12 12 12 12 32

times ranked

citing authors

docs citations

all docs

#	Article	IF	CITATIONS
1	Accuracy of CMOS-Based Piezoresistive Stress Sensor for Engineering Applications of Thermal Loading Condition: Theoretical Review and Experimental Validation. IEEE Sensors Journal, 2019, 19, 9139-9148.	4.7	12
2	Prognostic approaches for the wirebond failure prediction in power semiconductors: A case study using DPAK package. , $2015, , .$		10
3	<inline-formula> <tex-math notation="LaTeX">\$In Situ\$ </tex-math> </inline-formula> Failure Detection of Electronic Control Units Using Piezoresistive Stress Sensor. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2018, 8, 750-763.	2.5	10
4	Study of Thermal Aging Behavior of Epoxy Molding Compound for Applications in Harsh Environments. , 2019, , .		8
5	Concept of the 3 rd Generation of Reliability for Electronic Smart Systems., 2019,,.		4
6	In-situ service load monitoring of automotive electronic systems using silicon-based piezoresistive stress sensor. Microelectronics Reliability, 2020, 110, 113650.	1.7	3
7	Simulation Driven Design of Novel Integrated Circuits - Part 4: Method of Validation of Coupled Thermal and Thermo-mechanical Simulation. , $2018, \ldots$		1
8	Characterization of toughness of epoxy based molding compound and its implementation in FEM code. , 2020, , .		1
9	Simulation Driven Design of Novel Integrated Circuits Physics of Failure Simulation of the Electronic Control Modules for Harsh Environment Application. , 2016, , .		O
10	Effect of Time-Dependent Bulk Modulus on Reliability Assessment of Automotive Electronic Control Unit. , 2019, , .		0
11	Evaluation of Chip-Package Interaction by Means of Stress Sensors. IEEE Sensors Journal, 2022, 22, 12959-12966.	4.7	0
12	In-situ monitoring of thermo-mechanical induced stresses in electronic control unit $\hat{a} \in \hat{b}$ from the assembly to use in the field., 2022, , .		0